SLOVENSKI STANDARD
oSIST prEN IEC 62475:2025

01-junij-2025

Visokotokovne preskusne tehnike - Definicije in zahteve za preskusne toke in merilne sisteme

High-current test techniques - Definitions and requirements for test currents and measuring systems

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Techniques des essais à haute intensité - Définitions et exigences relatives aux courants d'essai et systèmes de mesure

Ta slovenski standard je istoveten z: **prEN IEC 62475:2025**

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ICS:

19.080	Električno in elektronsko preskušanje	Electrical and electronic testing

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2003-01.Slovenski inštitut za standardizacijo. Razmnoževanje celote ali delov tega standarda ni dovoljeno.

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42/455/CDV

COMMITTEE DRAFT FOR VOTE (CDV)

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SUPERSEDES DOCUMENTS:

42/439/CD, 42/453/CC

IEC TC 42 : HIGH-VOLTAGE AND HIGH-CURRENT TEST TECHNIQUES

SECRETARIAT:

Canada

SECRETARY:

Mr Howard G. Sedding

OF INTEREST TO THE FOLLOWING COMMITTEES:

TC 14,TC 17,SC 18A,TC 23,TC 32,TC 36,TC 37,TC 38,TC 73,TC 77,TC 90,TC 96,SC 121A,SC 121B

HORIZONTAL FUNCTION(S):

ASPECTS CONCERNED:

Electricity transmission and distribution

☒ SUBMITTED FOR CENELEC PARALLEL VOTING

Attention IEC-CENELEC parallel voting

The attention of IEC National Committees, members of CENELEC, is drawn to the fact that this Committee Draft for Vote (CDV) is submitted for parallel voting.

The CENELEC members are invited to vote through the CENELEC online voting system.

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TITLE:

High-current test techniques - Definitions and requirements for test currents and measuring systems

PROPOSED STABILITY DATE: 2026

NOTE FROM TC/SC OFFICERS:

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